4. (Amended) A method according to claim 1, whereby the first image (B_{1e}) and or the second image (B_{2e}) is shifted by calculation and whereby the position information assigned to the electric image signals is altered so at least on electronic phantom image is created as one of the images to make a comparison with.

5. (Amended) A method according to claim 1, whereby at least the first or second image (B_{2e}) is shifted by calculation (14) to the position of the other image (B_{1e}) and whereby the position information is altered relative to the shift ($\tilde{S}$) between the matrix positions so that at least one phantom image (B_{Ph1}) of the other image (B_{1e}) is created, and whereby comparison is performed between the phantom image ((B_{Ph1}) and the other image (B_{1e}).
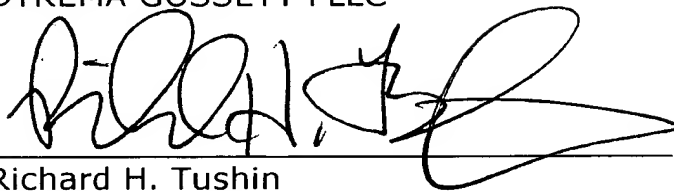
8. (Amended) A method according to claim 1, whereby it is concluded that impurities (Z) on the matrix are (coming) from the comparison-result image (Δ) and/or via the displaced image areas (ρ) in the imaging beam.

REMARKS

By this Preliminary Amendment claims 3, 4, 5 and 8 have been amended to depend from claim 1. Entry is in order.

Respectfully submitted,

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VERSION WITH MARKINGS TO SHOW CHANGES
MADE TO CLAIMS

U.S. Patent Appln. No. 09/821,792

3. (Amended) A method according to [one of the claims 1 or 2] claim 1, whereby electric image signals of the two images (B_{1e}, B_{2e}) are compared with one another, whereby sensor elements are identified as impurity-containing (Z), and whereby output signals provide a comparison result in the comparison-result image (Δ) indicating a match in at least a predetermined measure.

4. (Amended) A method according to [one of the claims 1 or 2] claim 1, whereby the first image (B_{1e}) and or the second image (B_{2e}) is shifted by calculation and whereby the position information assigned to the electric image signals is altered so at least on electronic phantom image is created as one of the images to make a comparison with.

5. (Amended) A method according to [one of the claims 1, 3 or 4] claim 1, whereby at least the first or second image (B_{2e}) is shifted by calculation (14) to the position of the other image (B_{1e}) and whereby the position information is altered relative to the shift ($\bar{S}$) between the matrix positions so that at least one phantom image (B_{Ph1}) of the other image (B_{1e}) is created, and whereby comparison is performed between the phantom image ((B_{Ph1}) and the other image (B_{1e}).

8. (Amended) A method according to [one of the claims 1 through 7] claim 1, whereby it is concluded that impurities (Z) on the matrix are (coming) from the comparison-result image (Δ) and/or via the displaced image areas (ρ) in the imaging beam.